RTP80 ROUGHNESS TESTER

Linear and radial roughness









Thanks to its easy handling and ease of use, the RTP80 roughness tester allows to perform the characterization of even the most complex surfaces in an easy and intuitive way.

RTP80 HEAD UNI

The bright 5.7 "color touch screen display combined with the icon interface allows the operator to quickly set the measurement parameters, position himself on the piece and perform the analysis.

The results obtained with the relative tolerances are immediately ready to be printed through the thermal printer integrated in the instrument. The graphs and parameters are all interactive to allow the operator to customize the presentation of the results. The RTP80 is suitable both for production environments, where it is possible to password protect the measurement settings for batch control, and for use in the metrology room where statistical analyzes can also be performed on the measurements made.

The RTP80 calculation unit can be combined with a series of measurement translators for the different types of parts.

TRANSLATOR TS7

The TS7, a small, compact and easy to handle sideshift, allows you to perform measurements even in the most difficult conditions, by holding it simply with one hand. The probe can be rotated by 90 ° and adjustable in height, can be folded inside to measure curved details. The maximum useful stroke is 16 mm.

TRANSLATOR TL90

SM Metrology Systems

The TL90 professional sideshift adopts an innovative rackless micrometric that allows you to position yourself on the piece with maximum precision with a useful range of 110 mm.

The probe is equipped with a plug-in connector to allow its quick change. Furthermore, thanks to the bistable system, it is possible to carry out measurements with and without shoe thanks to the SB10/60 probe and the internal reference for extremely precise mechanics that allows the evaluation of W parameters.

User friendly interface

Measurement Studio software - code: 1.404



Upside down and transverse measurement



Technical data

Product code: RTP80 + TS7 (code: 1.103 + 1.200) RTP80 + TL90 (code: 1.103 + 1.201)

Measuring range: ±250µm ±500µm Resolution: 0,001 µm 0,001 µm 1° ISO/DIN 1° ISO/DIN Accuracy class:

Cut-off length: 0,25 - 0,8 - 2,5 - 8 mm 0,25 - 0,8 - 2,5 - 8 mm Selectable from 1 to 5 Selectable from 1 to 19 Number of cut-offs:

Exploration ride: Up to 16 mm Up to 16 mm

Probe: Inductive rotable by 90 ° for lateral measurements Inductive rotable by 90 ° for lateral measurements

Printer: Integrated thermal printer Integrated thermal printer

54 parameters

(Ra, Rq, Rt, Rz, Rp, Rc, Rv, Rsk, Rku, Rsm, Rdc, RPc, Pa, Pq, Pt, Pp, Pc, Pv, Psm, Pdc, PPc, Wa, Wq, Wt, Wz, Wp, Wv, Wc, WSm, Wdc, WPc, Rk, Rpk, Pvk, Mr1, Mr2, Pt, Pdc, PPc, R, Rx, AR, Wte, W, AW, Wx, Rke, Rpke, Rvke, Mr1e, Measurement parameters:

Roughness, undulation, primary, total, lift curve and ordinate distribution. Graphs displayed:

Millimeters and inches Unit of measure:

Interface: 5,7-inch TFT touch screen color graphic display and 3 waterproof membrane buttons

Languages: Italian, French, English, German, Spanish and Portuguese

Up to 1000 measurements Memory:

RTP80 roughness tester, translator (TS7 or TL90), 110-230V battery charger, roughness specimen, transport case, user Standard equipment:

TRANSLATORS:

Code: 1.201

Compact and handy sideshift, it allows you to perform measurements in the most difficult conditions by simply hol-TS7

Code: 1.200 Maximum stroke of 25 mm

Professional translator with internal metrological reference that allows to characterize the W ripple parameters. Positioning micrometer on the piece with 110mm excursion, bistable nose piece for measurements with and without TL90

Maximum stroke of 50 mm.











Probe SB50 - code: 1.354

Probe SB110 - code: 1.358

Probe SB120 - code: 1.359

Probe SB120s - code: 1.360







ST2 granite stand 630x400mm - code: 1.401

ST3 stand 800x400 mm - codice: 1.413

ST4 motorized stand - codice: 1.418







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